S	e	a	rc	h	N	0	te	s
---	---	---	----	---	---	---	----	---



Application/Control No.	Applicant(s)/Patent under Reexamination		
10/621,755	HAN, KE		
Examiner	Art Unit		
Leila Malek	2611		

SEARCHED				
Class	Subclass	Date	Examiner	
375	362	8/30/2007	L.M.	
375	355	8/30/2007	L.M.	
375	354	8/30/2007	L.M.	

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
375	362	8/30/2007	L.M.		
375	355	8/30/2007	L.M.		
375	354	8/30/2007	L.M.		
	-				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST	8/30/2007	L.M.		
IEEE	8/30/2007	L.M.		
GOOGLE	8/30/2007	L.M.		
Inventor Name Search	8/30/2007	L.M.		
Consulted M. Ghayour	8/30/2007	L.M.		

Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/621,755	HAN, KE
Examiner	Art Unit
Leila Malek	2611

SEARCHED				
Class	Subclass	Date	Examiner	
375	362	8/30/2007	L.M.	
375	355	8/30/2007	L.M.	
375	354	8/30/2007	L.M.	
,				

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
375	362	8/30/2007	L.M.		
375	355	8/30/2007	L.M.		
375	354	8/30/2007	L.M.		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST	8/30/2007	Ŀ.M.
IEEE	8/30/2007	L.M.
GOOGLE	8/30/2007	L.M.
Inventor Name Search	8/30/2007	L.M.
Consulted M. Ghayour	8/30/2007	L.M.
i		·
		·
·		